

Form PTO-1449

ATTY. DOCKET NO.
M122-1898SERIAL NO.
10/050,348U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEAPPLICANT
Gurtej S. SandhuLIST OF ART CITED BY APPLICANT
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January 15, 2002GROUP
2813

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>SL</i>	AA	3,627,598	12-1971	McDonald et al.			
	AB	4,254,161	03-1981	Kemlage			
	AC	4,262,631	04-1981	Kubacki			
	AD	4,435,447	03-1984	Ito et al.			
	AE	4,882,649	11-1989	Chen et al.			
	AF	4,891,684	01-1990	Nishioka et al.			
	AG	4,980,307	12-1990	Ito et al.			
	AH	4,996,081	02-1991	Ellul et al.			
	AI	5,051,794	09-1991	Mori			
<i>SL</i>	AJ	5,142,438	08-1992	Reinberg et al.			

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
<i>SL</i>	AK	EP 0886308 A2	12-1998	EPO				
<i>SL</i>	AL	237243 a	04-2001	Japan				
	AM							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

<i>SL</i>	AN	Wolf, Stanley, Silicon Processing for the VLSI Era (1995), V.3, 648-9
<i>SL</i>	AO	Laughery et al., Effect of H ₂ Content on Reliability of ...
	AP	

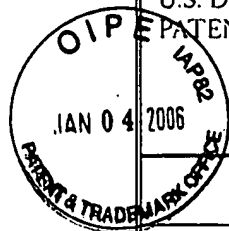
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<i>h</i>	AA	5,227,651	07-1993	Kim et al.			
	AB	5,237,188	08-1993	Iwai et al.			
	AC	5,324,679	06-1994	Kim et al.			
	AD	5,330,936	07-1994	Ishitani			
	AE	5,350,707	09-1994	Ko et al.			
	AF	5,376,593	12-1994	Sandhu et al.			
	AG	5,393,702	02-1995	Yang et al.			
	AH	5,397,748	03-1995	Watanabe et al.			
	AI	5,398,641	03-1995	Shih			
	AJ	5,459,105	10-1995	Matsuura			
	AK	5,969,397	10-1999	Grider, III et al.			
<i>h</i>	AL	6,040,249	03-2000	Holloway			

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<i>Sh</i>	AA	5,498,890	03/96	Kim et al.			
	AB	5,504,029	04/96	Murata et al.			
	AC	5,508,542	04/96	Geiss et al.			
	AD	5,523,596	06/96	Ohi et al.			
	AE	5,731,235	03/98	Srinivasan et al.			
	AF	5,821,142	10/98	Sung et al.			
	AG	5,844,771	12/98	Graettinger et al.			
	AH	5,851,603	12/98	Tsai et al.			
	AI	5,882,978	03/99	Srinivasan et al.			
	AJ	6,001,741	12/99	Alers			
	AK	6,087,236	07-2000	Chau et al.			
	AL	6,245,616 B1	06-2001	Buchanan et al.			
<i>Sh</i>	AM	6,150,226	11-2000	Reinberg			

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<i>JS</i>	AA	6,001,748	12/99	Tanaka			
	AB	6,008,104	12/99	Schrems			
	AC	6,051,865	04/00	Gardner et al.			
	AD	6,063,713	06/00	Doan			
	AE	6,077,754	06/00	Srinivasan et al.			
	AF	6,096,597	08/00	Tsu et al.			
	AG	6,111,744	08/00	Doan			
	AH	6,168,980	01/01	Yamazaki et al.			
	AI	6,207,985 B1	03/01	Walker			
<i>JS</i>	AJ	6,323,138 B1	11/01	Doan			

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<i>AA</i>	AA	6,348,420 B1	02/02	Raaijmakers et al.			
	AB	6,265,327	07/01	Kobayashi et al.			
	AC	6,350,707 B1	02/02	Liu et al.			
	AD	6,723,599 B2	04/04	Eppich et al.			
	AE	6,893,981 B2	05/05	Park et al.			
	AF	09/653,281	08/00	Beaman et al.			
	AG	2001/0036752	11/01	DeBoer et al.			
	AH	2002/0009861	08/98	Narwankar et al.			
	AI	2002/0052124	05/02	Raaijmakers et al.			
<i>AJ</i>	AJ	2003/0034518A1	02/03	Yoshikawa			

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